

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/822,130 | Applicant(s)/Patent Under Reexamination CHO ET AL. | |
| | Examiner David Q. Nguyen | Art Unit 2681 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-2002/0138229 A1 | 09-2002 | Wilborn et al. | 702/142 |
| * | B | US-6,529,850 B2 | 03-2003 | Wilborn et al. | 702/142 |
| * | C | US-6,246,885 B1 | 06-2001 | Black et al. | 455/553.1 |
| * | D | US-5,825,807 A | 10-1998 | Kumar, Derek D. | 375/130 |
| * | E | US-5,748,677 | 05-1998 | Kumar, Derek D. | 375/285 |
| * | F | US-6,272,168 B1 | 08-2001 | Lomp et al. | 375/222 |
| * | G | US-6,377,607 B1 | 04-2002 | Ling et al. | 375/130 |
| * | H | US-US 20050020219A1 | 01-2005 | Sih et al. | 455/130 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.